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The structure of SiF₄. By MASAO ATOJI and WILLIAM N. LIPSCOMB, *School of Chemistry, University of Minnesota, Minneapolis 14, Minnesota, U.S.A.*

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A determination of the Si-F bond distance at 1.56 ± 0.01 Å has been made from an X-ray diffraction study of single crystals of SiF₄ at -145° C. The structure of the solid derived by Natta (1930) on the basis of powder diffraction patterns is confirmed. These are 2 Si at 0, 0, 0 and $\frac{1}{2}, \frac{1}{2}, \frac{1}{2}$, and 8 F at x, x, x , etc., in the eightfold positions of T_d^2-I43m . The parameter $x = 0.165$ was determined by three-dimensional Fourier methods, with correction for termination of the series. The X-ray diffraction data are summarized in Table 1.

Table 1. Observed and calculated structure factors* for SiF₄

<i>hkl</i>	$ F_o $	$ F_c $	<i>hkl</i>	$ F_o $	$ F_c $
110	35.6	34.0	211	26.2	26.0
200	4.8	4.6	222	18.2	17.4
220	19.2	20.2	321	13.4	14.4
310	1.8	1.6	411	10.4	11.0
400	< 1.8	0.4	332	< 2.6	0.6
330	23.0	23.0	422	8.2	8.2
420	10.8	10.6	431	7.0	7.8
510	7.8	7.4	521	6.0	6.2
440	6.0	6.0	433	< 2.6	0.2
530	< 2.6	0.8	442	4.4	4.4
600	9.2	8.8	611	6.0	4.2
620	< 2.6	0.4	622	4.4	3.0
710	3.4	2.4	631	< 2.6	0.2
550	2.6	2.2	444	5.2	2.4

* The temperature factor is $\exp(-4.1 \sin^2 \theta / \lambda^2)$. The value of $R = \sum(|F_o| - |F_c|) / \sum|F_o|$ is 0.064 for observed reflections only, and 0.075 for all reflections.

Previous determinations of the Si-F bond distance have led to values of 1.59 Å (Natta, 1930), and 1.54 Å (Brockway & Wall, 1934; cf. Braune & Pinnow, 1937), which are probably less precise than our value. With the use of 0.71 Å as a radius for F (Andrychuk, 1951), and the corrected additivity relation (Schomaker & Stevenson, 1941), the 'normal' single-bond Si-F distance is 1.68 Å. Of the various explanations for the shortening of 0.12 Å in SiF₄, the one given by Pitzer (1948) seems most reasonable to us in view of the uniquely high electronegativity of F (cf. also Pauling, 1952). Even so, the effect here is remarkably large, comparable with that shown by the ions of the general type XO₄⁻ⁿ (Donohue & Shand, 1947).

In addition we have attempted to evaluate the crystal energy by methods similar to those of Heller (1941) but with the use of a R^{-12} repulsive potential, where R is the interatomic distance between non-bonded atoms. For this purpose the values of ΣR^{-n} have been evaluated for

Table 2. Values of ΣR^{-n} for interactions in the SiF₄ crystal (Values in Å⁻ⁿ)

	$\Sigma R^{-6} \times 10^6$	$\Sigma R^{-8} \times 10^7$	$\Sigma R^{-10} \times 10^8$	$\Sigma R^{-12} \times 10^9$
F...F	45788	39655	39365	40870
Si...F	10051	4301	2004	962
Si...Si	1077	408	168	71

the SiF₄ crystal, and since they may prove useful and represent fairly extensive calculations we have listed them in Table 2.

With the use of the crude model of a harmonic oscillator with a single frequency, we have calculated the crystal energy from the expression (cf. Heller, 1941)

$$E = \frac{N}{2} \sum_R \left[\mathcal{R}(R) - \frac{3}{4} \alpha^2 \epsilon R^{-6} - \frac{15}{4} \frac{\alpha^3 \epsilon^2}{e^2 f} R^{-8} - \frac{735}{32} \frac{\alpha^4 \epsilon^3}{e^4 f^2} R^{-10} - \frac{2835}{16} \frac{\alpha^5 \epsilon^4}{e^6 f^3} R^{-12} - \dots \right],$$

where N is Avagadro's number, $\mathcal{R}(R)$ is the repulsive energy, α is the bond polarizability here taken as one-quarter of the total polarizability (3.32 \AA^3) of SiF₄ and centered at the F atoms, $\epsilon = h\nu$ is the energy corresponding to the principal specific frequency ν and is approximately equal to the ionization potential (17.4 e.V.) and $f = 4\pi m e^2 \alpha / e^2 h^2 = 2.26$ is the oscillator strength (Margenau, 1939). The repulsive energy was estimated as C_r/R^{12} , with $C_r = 58.1 \times 10^{-10}$ ergs Å¹², from the pair interactions between F atoms determined from interactions between gaseous F₂ molecules. The calculated attractive energy of -5.9 kcal./mole and the repulsive energy of ± 1.7 kcal./mole thus lead to an estimated crystal energy of -4.2 kcal./mole. The observed value is -6.2 kcal./mole (Patnode & Papish, 1930).

This agreement is not regarded as particularly good, especially in view of the extreme assumption of placement of the polarizability of the molecule at the four F atoms. This assumption leads to a maximum attractive energy for this model. These results suggest that the constants in the F...F interatomic interaction potential are not known with sufficient accuracy in the range of distances which occur in solid SiF₄. Certainly the use of the F...F interaction obtained from gaseous F₂ in the form of a Lennard-Jones 6:12 potential has proved to be unsatisfactory. However, if a satisfactory potential-energy constant becomes available, the results in Table 2 will become useful.

References

- ANDRYCHUK, D. (1951). *Canad. J. Phys.* **29**, 151.
 BRAUNE, H. & PINNOW, P. (1937). *Z. phys. Chem.* **B**, **35**, 239.
 BROCKWAY, L. O. & WALL, F. T. (1934). *J. Amer. Chem. Soc.* **56**, 2373.
 DONOHUE, J. & SHAND, JR., W. (1947). *J. Amer. Chem. Soc.* **69**, 222.
 HELLER, R. (1941). *J. Chem. Phys.* **9**, 154.
 MARGENAU, H. (1939). *Rev. Mod. Phys.* **11**, 1.
 NATTA, G. (1930). *Gazz. chim. ital.* **60**, 911.
 PATNODE, W. I. & PAPISH, J. (1930). *J. Phys. Chem.* **34**, 1494.
 PAULING, L. (1952). *J. Phys. Chem.* **56**, 361.
 PITZER, K. S. (1948). *J. Amer. Chem. Soc.* **70**, 2140.
 SCHOMAKER, V. & STEVENSON, D. P. (1941). *J. Amer. Chem. Soc.* **63**, 37.